Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/020,744	WEISE, JON	
Examiner	Art Unit	
Edgardo San Martin	2837	

SEARCHED					
Subclass	Date	Examiner			
-					
		<u> </u>			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
181	129,130	2/14/2005	ESM		
	135				
			7		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
All of the previous searches were updated	2/14/2005	ESM			